HOMEWORK: 02 K.SURYA PRAKASH EE18BTECH11026

Question: 01

1. Transient simulations for NMOS and PMOS, to find the  $R_{eq}$  (L = 0.18um process)

$$R_{eq} \sim (R_{Vdd} + R_{Vdd/2})/2$$

#### 1.1 NMOS : For Vdd = 1.8V

```
*** For Ques: 1. NMOS

*** Vgs = 1.8V, init Vds = 1.8V.,

** M1 --> 1. W/L = 240/180

** M2 --> 2. W/L = 400/180

.include TSMC180.lib
.model nch_tt nmos (level = 8)

Vgs g 0 1.8

V_am d am 0V ** ammeter

C am 0 1e-12 IC = 1.8V

*M1 d g 0 0 nch_tt W=240n L = 180n

M2 d g 0 0 nch_tt W=400n L = 180n

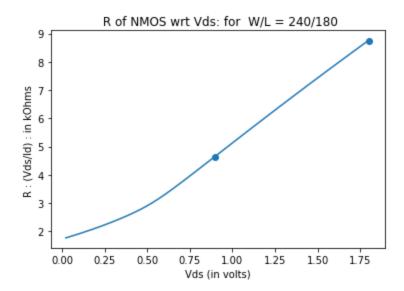
.ic V(am) = 1.8V
.control

tran 1p 13n

*plot V(am)

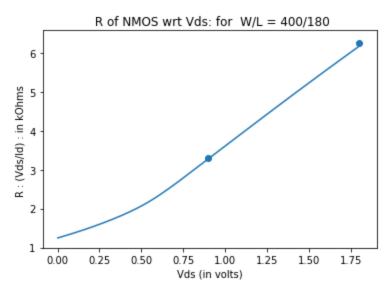
*plot -i(V_am) vs V(am) title "I vs V"
plot V(am)/-i(V_am) vs V(am) title "Res vs V: M1 "
wrdata 1.a.n.2.dat V(am) V(am)/-i(V_am)
```

# 1.1.1 W/L = 240/180



Calculating  $R_{eq} = (8.8 + 4.7)/2 = 6.75 \text{ kOhm}$ 

## 1.1.2 W/L = 400/180



Calculating  $R_{eq} = (6.2 + 3.36)/2 = 4.78 \text{ kOhm}$ 

## 1.2 : PMOS : for $V_{dd} = -1.8V$

```
**** For Ques: 1. PMOS

**** Vgs = -1.8V, init Vds = -1.8V.,

** M1 --> 1. W/L = 240/180

** M2 --> 2. W/L = 400/180

.include TSMC180.lib
.model pch_tt pmos (level = 8)

Vgs g 0 -1.8

V_am d am 0 ** ammeter

C am 0 1e-12 | C = -1.8V

*M1 d g 0 0 pch_tt W=240n L = 180n

M2 d g 0 0 pch_tt W=400n L = 180n

.ic V(am) = -1.8V

.control

tran .5p 30n

*plot -V(am)

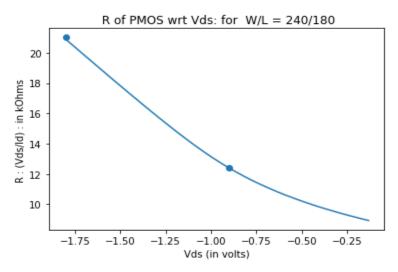
*plot -i(V_am) vs V(am) title "I vs V"

plot V(am)/-i(V_am) vs V(am) title "Res vs V: M1 "

wrdata 1.a.p.2.dat V(am) V(am)/-i(V_am)

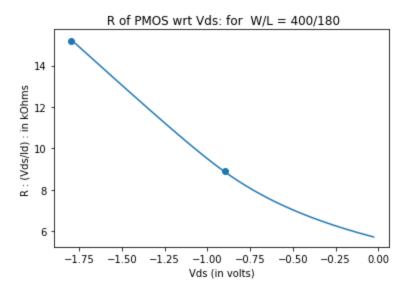
.endc
.end
```

# 1.2.1 W/L = 240/180



## Calculating $R_{eq} = (21 + 12.4)/2 = 16.7 \text{ kOhm}$

1.2.2 : W/L = 400/180



Calculating  $R_{eq} = (15.2 + 8.9)/2 = 12.05 \text{ kOhm}$ 

**b)** Results for different Vdd : **Trend of**  $R_{eq}$  **w.r.t**  $V_{dd}$  By doing analysis for different  $V_{dd}$  :( initial capacitor voltage and  $V_{gs}$ ). The below are the results for  $R_{eq}$  at different Vdd.

For W/L: 240/180

Vdd   (in V)	Req for NMOS (k Ohm)	Req for PMOS(k Ohm)
1.8	6.75	16.7
1.5	7.53	21.8

1.2	9.3	32.6
0.9	14.47	62.5
0.6	63.5	251

For W/L: 400/180:

Vdd   (in V)	Req for NMOS (k Ohm)	Req for PMOS(k Ohm)
1.8	4.78	12.05
1.5	5.375	15.25
1.2	6.75	22.1
0.9	10.55	40.65
0.6	51.3	193.7

#### **Observations:**

- 1. We can see that there is a deviation with the values mentioned in the Textbook, where results are produced for (W/L = 1).
- 2.  $R_{\text{eq}}$  is inversely proportional to (W/L) ratio.
- 3. We can observe that when we scale the obtained  $R_{\rm eq}$  with (W/L) we get the values closer to that of the TB values.

- 4. Although there will be differences, since the simulation is done for a 0.25u process (in the TB), while we performed for a 0.18u process
- 5. Another observation is that  $R_{eq}$  of PMOS is relatively high when compared to that of NMOS for the same  $V_{dd}$ , reason being that since PMOS works with the mobility of holes which is less when compared to the mobility of electrons in NMOS. This will result in less current, which is seen as a high resistance in PMOS devices.
- 6.  $R_{eq}$  decreases as  $V_{dd}$  increases, and reaches a constant low value for high  $V_{dd}$ . As  $V_{dd}$  increases, the mosfet moves from : Cutoff to saturation region. At cutoff very less current flows , and seen as high resistance. And for high  $V_{dd}$ , it reaches saturation, where current is constant and high and does not depend on Vgs. This is seen as a low ON resistance.

\_\_\_\_\_\_

# **Question: 02 MOSFET Capacitance**

$$V_{app} = V_{CM} + (1/(2.pi.f)) \sin(wt)$$
  
 $I_{q} = C*\cos(wt)$ 

The amplitude of the gate current gives the gate capacitance.

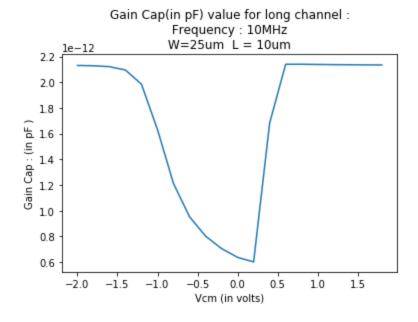
#### A. CV CHARACTERISTICS:

```
cm + sin(wt), Vds = 0V., sweeping vcm
                    0 SIN(0 {1/(2*3.14*f)} f 0 0 0)
meas tran i_max FIND i(Vcm) AT = 1u
*meas tran i_max FIND i(Vcm) AT = 10n
    ot i(Vcm) xlabel "Current at Vcm = $&v"
```

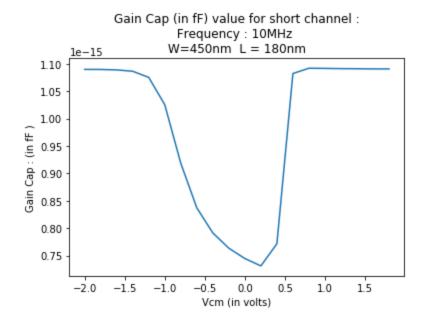
let v = v + 0.2 let loop = loop + 1 end plot c\_vec vs v\_vec wrdata 2.b.dat c\_vec vs v\_vec .endc .end

## Generating C vs $V_{cm}$ graph. Frequency: 10MHz

A.1. W/L = 2.5,: Long channel L =  $10\mu m$ , W =  $25\mu m$ .



A.2. Short channel : L = 180nm, W = 450nm



#### **OBSERVATIONS**

- **1.**Long channel capacitance (pF) is higher than short channel capacitance(fF).
- **2.**The highest value depends on  $C_{OX}$  \* W \* L . Hence it is evident that long channels have a higher cap in order than short channels.
- **3.**The overlap capacitance comes into picture in the short channel case (since it's very small).

## **Explaining the graph:**

**3.1 Cutoff :** The Gate-Bulk cap  $(C_{GBS})$  accounts for the left side of the graph (< 0V), which gradually reduces as Vcm (i.e;Vgs ) increases, due to the formation of channel

.

**3.2 Linear :** A complete channel is formed , later on the capacitance is provided by the source and the drain equally and  $C_{\text{GBS}}$  ceases to exist.

### **B**) Low vs High Frequency:

Plots for 10MHz are shown above.

#### Plots for 10 GHz

Gain Cap(in pF) value for long channel : Frequency: 10MHz  $W=25um\ L=10um$ 2.2 2.0 1.8 Gain Cap: (in pF) 1.6 1.4 1.2 1.0 0.8 0.6 -2.0 -1.5 -1.0-0.5 0.0 0.5 1.0 1.5 Vcm (in volts)

Gain Cap(in fF) value for short channel : Frequency: 10GHz W=450nm L = 180nm le-15 1.10 1.05 1.00 0.95 0.90 0.85 0.80 0.75 -2.0 -1.5 -1.0 -0.5 0.0 0.5 1.0 1.5 Vcm (in volts)

#### **Observations:**

- 1. We can see that both plots are almost identical with a similar range.
- 2. Long channel continuous to be in pF range, and short channel in fF range. (due to its dependence on W\*L).
- 3. Due to abundant charges provided by source and the drain, we are able to find similar plots at different frequencies, unlike a MOSCAP, which shows different characteristics due to absence of drain and source.

\_\_\_\_\_

### Question: 03



VTN = 1VTP1 = 0.3V

- a) which one consumes static power? at high input?
- $\rightarrow$  (i), (ii), (iii).
- # cmos (iv), has no current flow due to priesence of a PMOS (at OFF state)
- # Another cases, since NMOS is ON current flows >> static power consumed
  - b) Static power at low input?

    > None T
- No current is desavon, since PMOS

  NMOS are off state in every care
- (c) VOH = 1.2 V % (2) (21) (1V)

(d) Vol = 0 v ?

Reason: Since boti
For 2, 21, 111 3 current is decaron

divider network => Hence Vout = 0

# For CMOS?

PMOS is open => Nout=0

(e) (i) (iii)

All except CMOS au dependent

on Size of dévices

#### **Question 04**

y VM: :- VIN= Vout > Ktw (NMOS in Saturation) \* Klw (VM-VT) = VDD-VM 21 172.5×10 (VM-0.43) = 2.5-VM 12.9 (VM-0.43) = 2.5-VM Solving the Quad egu. Vm=0.79 V

(b) \* VIL, VIH =? For VIL, VIH = dVout, -1

· VIL (NMOS is susturation sign).

VDD-Vout = K'W (VIN-VT)2

> Derivating wet. Vorting

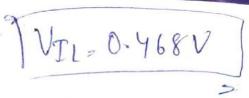
 $=\frac{1}{RL}\left(\frac{dV_{out}}{dV_{IN}}\right)=\frac{k'N}{2L}(2)(V_{IN}-V_T)$ 

=) = K'W (VIN-VT)

=> VIL=VIN= L +VT

= 10° + 0°43 (1035)\* (15×18)

VIL 2 0.468 V



\* VIH (NMOS in linear rign)

-1 dvout = KW (VIN-VT) dvout + Vout
Re dvin = KW (VIN-VT) dvout + Vout

- 2 Vout dvout

=> = K'n [VT-Vin+ 2. Vout]

L RLK'W 2 VT-VIN+2 Vout

=) Vin= VT+ 2. Vout - L - ) (2)

-) 2.5-Vout - RIKIN ((2 vout - L) Vout.

on Solving this; \$0.253 V Vout = => Vin > Vin > 2 Vout + VT @ 0.012 D.899V => VIH= Vin=

B) contd. Moise margin

NMH = VOH - VIH = 2.5 - 0.9 > 1.6 V

NML = VIL - VOL 20.468 - 0.046 z 0.42

(e) Peak gain => happens at Vm

(Vin > Vout) => Saturation sgn

k'W (Vm-VT) = VDD-Vout

RL

>> SVout | (>>>> gain)

Vin=Vm

>> KW (2CVm-VT)) = -1 (3Vout)

RL (3Vin)

-> -RLK'W (Vm-VT) = gain (peak)

Solving
Peakgain: = 25.875 (0.793-0.43)
- 9.38 V

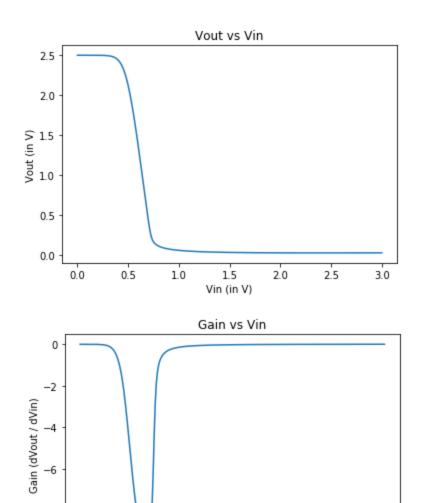
Peakgain = -9.38 V

#### Ques 5: NMOS

## 5a) VTC plots:

```
** Q5. VTC of NMOS with res
.include TSMC180.lib
.model nch_tt nmos
```

Plotting the gain (dVout/ dVin) and Vout vs Vin For  $R_L = 75k$  Ohms



Peakgain = -9.43

1.5 Vin (in V) 2.0

2.5

3.0

1.0

0.5

-8

0.0

Parameters	Observed Value
V <sub>IL</sub>	0.387 V
V <sub>IH</sub>	0.774 V
V <sub>OH</sub>	2.49 V

V <sub>OL</sub>	0.031 V
V <sub>M</sub>	0.67 V
Peak gain	-9.43

# 5b) Change of threshold and peak gain w.r.t load resistance.

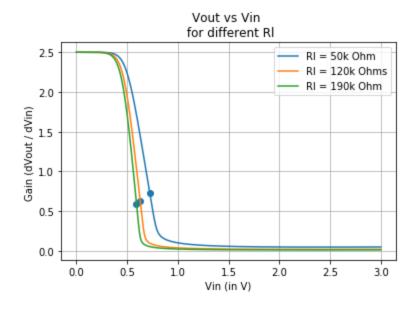
Varying resistance: checking for: 50k, 120k, 190k.

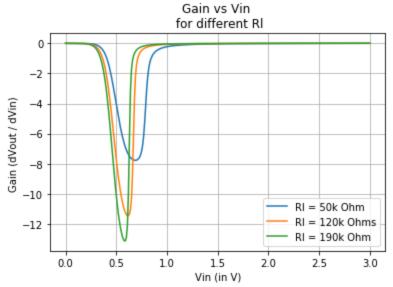
```
include TSMC180.lib
.model nch_tt nmos

M vout input 0 0 nch_tt W=0.54u L=0.18u
R vout vdd 75k
Vin input 0 dc
V vdd 0 2.5V
.control
dc Vin 0V 3V 0.01V R 50k 200k 70k

plot V(vout)
plot deriv(V(vout))
let diff=deriv(V(vout))
let peakgain=deriv(diff)
meas dc vil find V(input) when diff=-1 cross=1
meas dc vih find V(input) when V(input)=0 cross=1
meas dc vol find V(vout) when V(input)=2.5 cross=1
meas dc vol find V(vout) when V(input)=V(vout) cross=1
meas dc vm find V(vout) when V(input)=V(vout) cross=1
meas dc gain_peak find diff when peakgain=0

wrdata 5.b.1.dat V(vout) vs v(input)
wrdata 5.b.2.dat deriv(V(vout)) vs v(input)
.endc
.end
```





#### **Observations:**

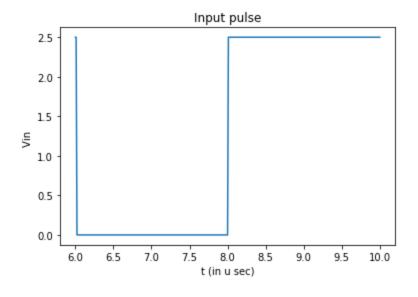
- 1. As  $R_L$  increases,  $V_M$  decreases, this is a consequence of the Pull down network becoming stronger.
- 2. Also the peak gain increases by magnitude. This happens due to the movement of  $V_{\rm M}$  towards  $V_{\rm IL}$ , hence the slope needs to drop at a high rate, this inturn increases the peak gain.

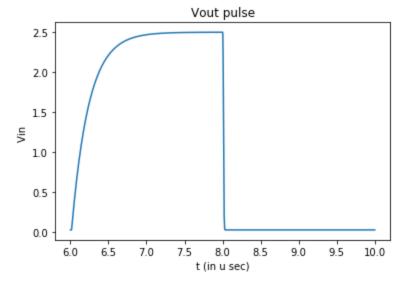
# **5c.**) **Implementing an inverter**: Testing with a square pulse of f = 250k Hz, $C_L = 3pF$ .

```
meas tran tin_half1 when V(input) = vin_half cross = 1 meas tran tin_half2 when V(input) = vin_half cross = 2
 let tpl = tr_half_1 - tin_half1
let tph = tr_half_2 - tin_half2
let tp =(tpl+tph)/2
```

print tr tf print tpl tph print tp

wrdata 5.c.1.dat V(input) wrdata 5.c.2.dat V(vout) .endc .end





#### Parameters obtained from the simulation

Parameter	Value
t <sub>r</sub>	494.04 ns
$t_{f}$	14.37 ns
<b>t</b> <sub>plh</sub>	154.25 ns
t <sub>phl</sub>	7.79 ns
t <sub>p</sub>	81.07 ns

#### Comment on t<sub>r</sub> and t<sub>f</sub> ..

 $T_r >> T_f$  , reason being the RC circuit changes when during the transition. For rise time we consider  $R_{\text{L}}$  , while for the fall time we consider  $R_{\text{ON}}$  . Since  $R_{\text{ON}} < R_{\text{L}}$  here. The capacitor charges and discharges at different rates.

- Geometric parameters: The max. Operating frequency for a particular MOSFET depends on t<sub>p</sub> (propagation delay), i.e; how fast will it be responding for the switch. T<sub>p</sub> inturn depends on the R<sub>eq</sub> and thus depends on the (W/L) ratio.
- Max. operating frequency:  $f_{max} = 1/t_p = 1/(81.07 \text{ ns}) = 12.33 \text{ MHz}$

$$P_{D} = C_{L} * (V_{gs} - V_{t}) * V_{DD} * f_{max}$$

## = 0.225 mW

\_\_\_\_\_

## THE END